

#### **Features**

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q<sub>rr</sub>)
- Halogen free, RoHS compliant

#### **Benefits**

- · Reduce switching losses and minimize gate ringing
- · Higher system efficiency
- · Reduce cooling requirements
- Increase power density
- Increase system switching frequency

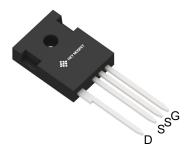
## **Applications**

- Renewable energy
- EV battery chargers
- High voltage DC/DC converters
- Switch Mode Power Supplies

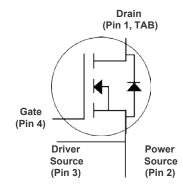




Ordering Part Number	Package	Qty(PCS)
C3M0040120K	TO-247-4L	30

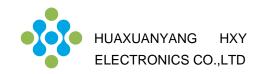


TO-247-4L



# Maximum Ratings (T<sub>c</sub> = 25 °C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions
$V_{DSmax}$	Drain - Source Voltage	1200	V	$V_{GS} = 0 \text{ V}, I_{D} = 100  \mu\text{A}$
$V_{GSmax}$	Gate - Source Voltage (dynamic)	-10/+25	٧	AC (f >1 Hz)
$V_{GSop}$	Gate - Source Voltage (static)	-5/+20	V	Static
	In Continuous Drain Current		Α	V <sub>GS</sub> = 15 V, T <sub>C</sub> = 25°C
l <sub>D</sub>	Continuous Diain Current	57	V <sub>GS</sub> = 15 V, T <sub>C</sub> = 100°C	
I <sub>D(pulse)</sub>	Pulsed Drain Current	TBD	А	Pulse width t <sub>P</sub> limited by T <sub>jmax</sub>
$P_{D}$	Power Dissipation	405	W	T <sub>c</sub> =25°C, T <sub>J</sub> = 175 °C
$T_{J}$ , $T_{stg}$	Operating Junction and Storage Temperature	-40 to +175	°C	
T <sub>L</sub>	Solder Temperature	260	°C	1.6mm (0.063") from case for 10s



**Electrical Characteristics** (T<sub>C</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions	Note	
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	1200			V	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 100 μA		
V Cota Through ald Valtage	2.0	2.5	4.0	V	$V_{DS} = V_{GS}$ , $I_D = 10 \text{ mA}$	F: 44		
$V_{\text{GS(th)}}$	Gate Threshold Voltage		1.5		V	$V_{DS} = V_{GS}$ , $I_D = 10$ mA, $T_J = 175$ °C	Fig. 11	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current		1	50	μΑ	V <sub>DS</sub> = 1200 V, V <sub>GS</sub> = 0 V		
I <sub>GSS</sub>	Gate-Source Leakage Current		10	200	nA	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V		
		-200	-10		nA	$V_{GS} = -10 \text{ V}, V_{DS} = 0 \text{ V}$		
P	Drain-Source On-State Resistance		40	50	mΩ	V <sub>GS</sub> = 20 V, I <sub>D</sub> = 40 A	Fig. 4, 5, 6	
R <sub>DS(on)</sub>	Dialii-30dice Oil-3tate Nesistance		59		11122	V <sub>GS</sub> = 20 V, I <sub>D</sub> = 40 A, T <sub>J</sub> = 175°C		
a.	Transconductance		10.4		S	V <sub>DS</sub> = 20 V, I <sub>DS</sub> = 40 A	Fig. 7	
g <sub>fs</sub>	Transconductance		7.7			V <sub>DS</sub> = 20 V, I <sub>DS</sub> = 40 A, T <sub>J</sub> = 175°C		
$C_{iss}$	Input Capacitance		2101					
Coss	Output Capacitance		161		pF	$V_{GS} = 0 \text{ V}, V_{DS} = 1000 \text{ V}$ f=100kHz	Fig. 17,	
$C_{rss}$	Reverse Transfer Capacitance		14			V <sub>AC</sub> = 25 mV		
Eoss	Coss Stored Energy		90		μJ		Fig. 16	
Eon	Turn-On Switching Energy (SiC Diode FWD)		1100		μJ	$V_{DS} = 800 \text{ V}, V_{GS} = -5 \text{ V}/+20 \text{ V}, I_{D} = 40 \text{A},$	Eig 26	
E <sub>OFF</sub>	Turn Off Switching Energy (SiC Diode FWD)		900		μυ	$R_{G(ext)} = 2.5\Omega$ , L= 100 $\mu$ H, Tj = 175°C	Fig. 26	
$t_{\text{d(on)}}$	Turn-On Delay Time		22					
t <sub>r</sub>	Rise Time		49		l	$V_{DD} = 800 \text{ V}, V_{GS} = -5 \text{ V}/20 \text{ V}$ $R_{G(ext)} = 2.5 \Omega, I_D = 40 \text{ A}$ Timing relative to $V_{DS}$	Fig. 27	
$t_{d(off)}$	Turn-Off Delay Time		71		ns			
t <sub>f</sub>	Fall Time		23		]			
R <sub>G(int)</sub>	Internal Gate Resistance		1.7		Ω	f = 1 MHz, V <sub>AC</sub> = 25 mV		
$Q_{gs}$	Gate to Source Charge		33			V <sub>DS</sub> = 800 V. V <sub>GS</sub> = -5 V/20 V		
$Q_{\text{gd}}$	Gate to Drain Charge		51		nC	$I_D = 40 \text{ A}$	Fig. 12	
Qg	Total Gate Charge		131					

# Reverse Diode Characteristics (T<sub>c</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
V Diada Farrand Veltage	Diode Forward Voltage	4.1		V	V <sub>GS</sub> = -5 V, I <sub>SD</sub> = 20 A, T <sub>J</sub> = 25 °C	Fig. 8,
V <sub>SD</sub>	Diode Porward Voltage	3.5		V	V <sub>GS</sub> = -5 V, I <sub>SD</sub> = 20 A, T <sub>J</sub> = 175 °C	9, 10
Is	Continuous Diode Forward Current		83	А	V <sub>GS</sub> = -4 V, T <sub>C</sub> = 25°C	Note 1
I <sub>S, pulse</sub>	Diode pulse Current		TBD	А	$V_{GS} = -4 \text{ V}$ , pulse width $t_P$ limited by $T_{jmax}$	Note 1
t <sub>rr</sub>	Reverse Recover time	56		ns		
Q <sub>r</sub>	Reverse Recovery Charge	508		nC	$V_{GS} = -5 \text{ V}, I_{SD} = 40 \text{ A}, V_{R} = 800 \text{ V}$ $dif/dt = 2250 \text{ A}/\mu\text{s}, T_{I} = 175 \text{ °C}$	Note 1
I <sub>rrm</sub>	Peak Reverse Recovery Current	18		А	. ,	

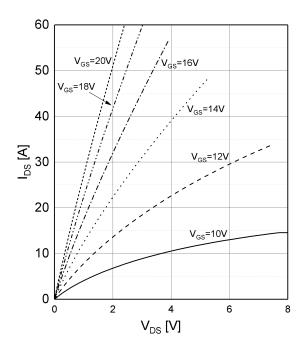
# **Thermal Characteristics**

Symbo	I Parameter	Тур.	Unit	Test Conditions	Note
Rejc	Thermal Resistance from Junction to Case	0.25			Fig. 24
R <sub>eJA</sub>	Thermal Resistance From Junction to Ambient	40	°C/W		Fig. 21

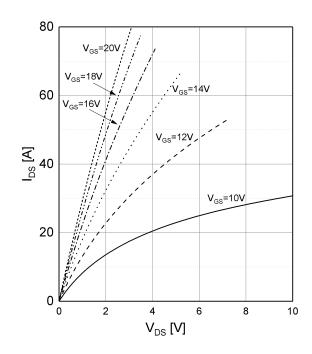


# **Typical Characteristics**

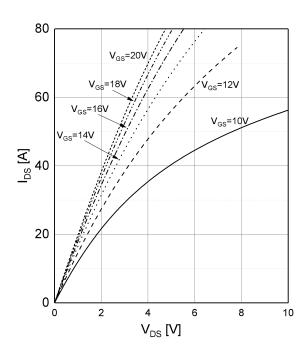
Output characteristics  $I_{DS}=f(V_{DS})$ ,  $T_{J}=-55$ °C



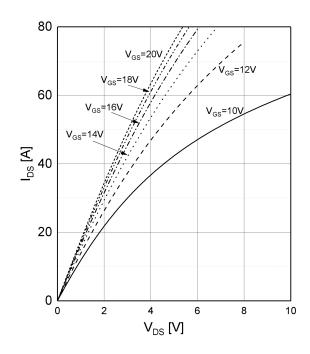
Output characteristics I<sub>DS</sub>=f(V<sub>DS</sub>), T<sub>J</sub>=25°C



Output characteristics  $I_{DS}=f(V_{DS})$ ,  $T_J=150$ °C

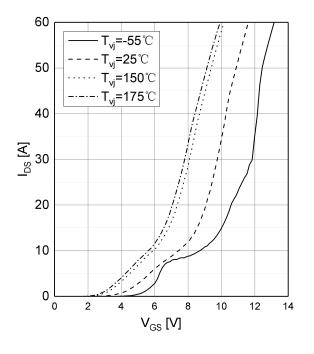


Output characteristics I<sub>DS</sub>=f(V<sub>DS</sub>), T<sub>J</sub>=175°C

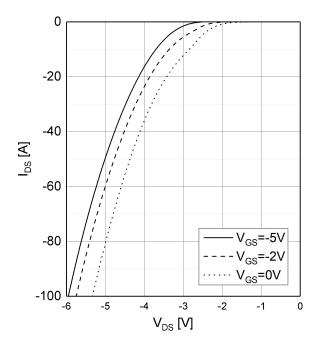




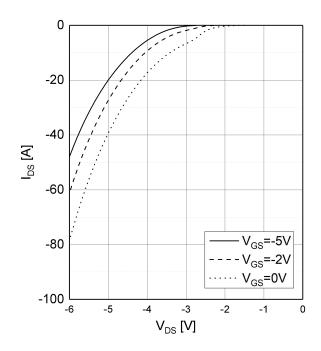
Transfer Characteristics  $I_{DS}$ =f( $V_{GS}$ ),  $V_{DS}$ =20V



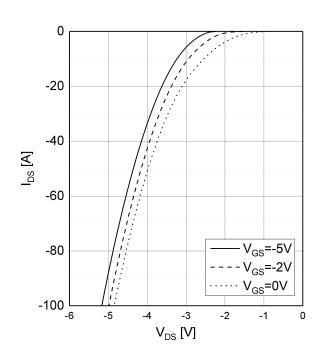
Body Diode Characteristics  $I_{DS} = f(V_{DS}), T_J = 25^{\circ}C$ 



Body Diode Characteristics  $I_{DS} = f(V_{DS})$ ,  $T_J = -55$ °C

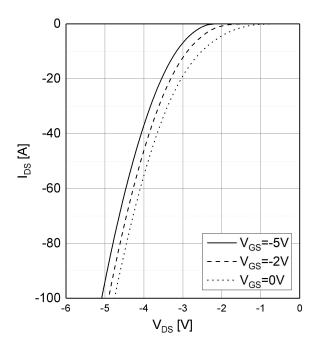


Body Diode Characteristics I<sub>DS</sub> =f(V<sub>DS</sub>), T<sub>J</sub>=150°C

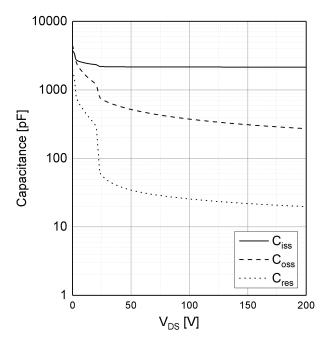




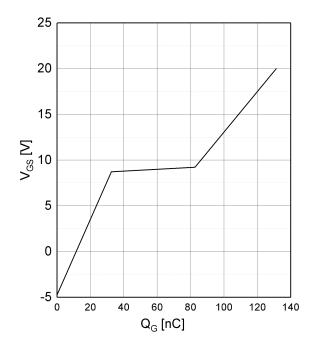
Body Diode Characteristics  $I_{DS} = f(V_{DS}), T_J = 175$ °C



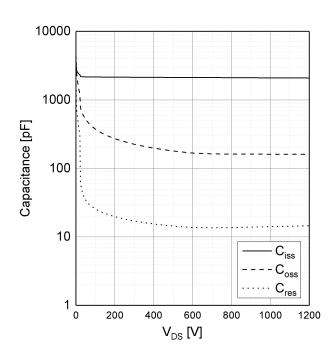
Capacitances vs Drain-Source Voltage (0-200V)  $C=f(V_{DS})$ ,  $T_j=25$ °C,  $V_{AC}=25$ mV, f=100KHz



Gate Charge Characteristics  $V_{GS}$  =f( $Q_G$ ),  $I_{DS}$ =40A,  $V_{DS}$ =800V,  $T_J$ =25 $^{\circ}$ C

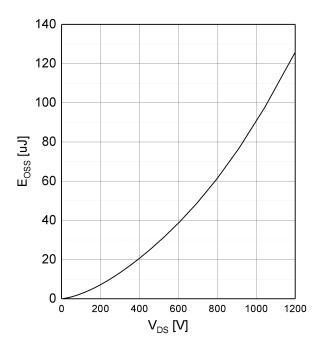


Capacitances vs Drain-Source Voltage (0-1200V)  $C=f(V_{DS})$ ,  $T_j=25^{\circ}C$ ,  $V_{AC}=25$ mV, f=100KHz

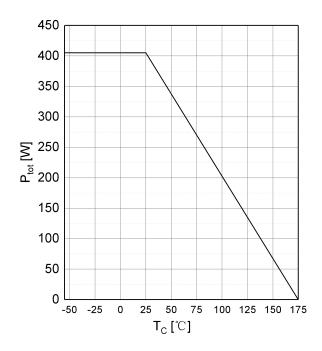




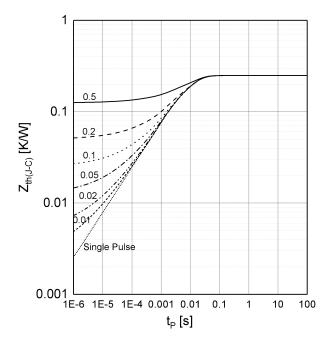
# Output Capacitor Stored Energy E<sub>OSS</sub> =f(V<sub>DS</sub>), T<sub>J</sub>=25°C



 $\begin{aligned} & \text{Maximum Power Dissipation Derating} \\ & P_{tot} \!=\! f(T_C), T_J \!\!\leq\! 175^{\circ} \! \text{C} \end{aligned}$ 



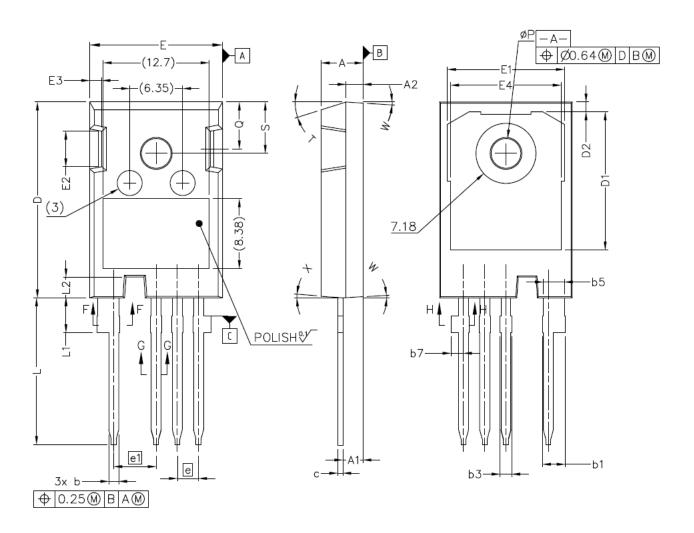
Transient Thermal Impedance (Junction to Case)  $Z_{th(J-C)}=f(t)$ ,  $T_C=25$ °C

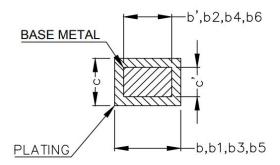




# **Package Dimensions**

Package TO-247-4L





SECTION "F-F", "G-G" AND "H-H" SCALE: NONE



# **Package Dimensions**

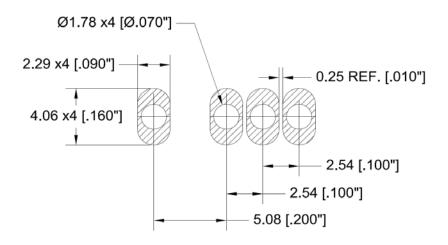
Package TO-247-4L

### NOTE;

- 1. ALL METAL SURFACES: TIN PLATED, EXCEPT AREA OF CUT
- 2. DIMENSIONING & TOLERANCEING CONFIRM TO ASME Y14.5M-1994.
- 3. ALL DIMENSIONS ARE IN MILLIMETERS. ANGLES ARE IN DEGREES.
- 4. 'N' IS THE NUMBER OF TERMINAL POSITIONS

SYM	MILLIMETERS				
STIVI	MIN	MAX			
Α	4.83	5.21			
A1	2.29	2.54			
A2	1.91	2.16			
b`	1.07	1.28			
b	1.07	1.33			
b1	2.39	2.94			
b2	2.39	2.84			
b3	1.07	1.60			
b4	1.07	1.50			
b5	2.39	2.69			
b6	2.39	2.64			
b7	1.30	1.70			
c`	0.55	0.65			
С	0.55	0.68			
D	23.30	23.60			
D1	16.25	17.65			
D2	0.95	1.25			
E	15.75	16.13			

SYM	MILLIMETERS				
31101	MIN	MAX			
E1	13.10	14.15			
E2	3.68	5.10			
E3	1.00	1.90			
E4	12.38	13.43			
е	2.54 BSC				
e1	5.08 BSC				
Ν*	4				
L	17.31	17.82			
L1	3.97	4.37			
L2	2.35	2.65			
ØΡ	3.51	3.65			
Q	5.49 6.00				
S	6.04 6.30				
Т	17.5° REF.				
W	3.5° REF.				
Χ	4° REF.				





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